

N-Channel 250 V (D-S) MOSFET

PRODUCT SUMMA	RY	
V _{DS} (V)	250)
R _{DS(on)} (Ω)	$V_{GS} = 10 \text{ V}$	2.0
Q _g (Max.) (nC)	8.2	
Q _{gs} (nC)	1.8	
Q _{gd} (nC)	4.5	
Configuration	Sing	le

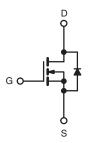
FEATURES

- Surface mount
- Available in tape and reel
- Dynamic dV/dt rating
- Repetitive avalanche rated
- · Fast switching
- Ease of paralleling
- Simple drive requirements









N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (To	c = 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	250		
Gate-Source Voltage		V_{GS}	± 20	V		
Continuous Drain Current	V at 10 V	T _C = 25 °C T _C = 100 °C	1	0.79		
Continuous Drain Current	V _{GS} at 10 V	T _C = 100 °C	I _D	0.50	Α	
Pulsed Drain Current ^a			I _{DM}	6.3		
Linear Derating Factor				0.025	W/°C	
Linear Derating Factor (PCB Mount) e				0.017		
Single Pulse Avalanche Energy b	gle Pulse Avalanche Energy ^b		E _{AS}	50	mJ	
Repetitive Avalanche Current a			I _{AR}	0.79	А	
Repetitive Avalanche Energy a			E _{AR}	0.31	mJ	
Maximum Power Dissipation	T _C =	T _C = 25 °C		3.1	w	
Maximum Power Dissipation (PCB Mount) e	T _A =	T _A = 25 °C		2.0	VV	
Peak Diode Recovery dV/dt ^c	-		dV/dt	4.8	V/ns	
erating Junction and Storage Temperature Range T _J , T _{stg} -55 to +150		°C				
Soldering Recommendations (Peak Temperature)	d for	10 s	_	300		

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \,^{\circ}\text{C}$, $L = 128 \,\text{mH}$, $R_g = 25 \,^{\circ}\text{C}$, $I_{AS} = 0.79 \,\text{A}$ (see fig. 12). c. $I_{SD} \le 2.7 \,\text{A}$, $I_{AS} = 0.79 \,\text{A}$, $I_{AS} = 0.79 \,\text{A}$ (see fig. 12).
- d. 1.6 mm from case.
- e. When mounted on 1" square PCB (FR-4 or G-10 material).



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient (PCB Mount) ^a	R _{thJA}	-	-	60	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	40		

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		^		I.	·	•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		250	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.39	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 20 V	-	-	± 100	nA
Zone Ooto Voltana Dusia Ormant		V _{DS} =	$V_{DS} = 250 \text{ V}, V_{GS} = 0 \text{ V}$		-	25	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 200 V	/, V _{GS} = 0 V, T _J = 125 °C	-	-	250	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 0.47 A ^b	-	2.0	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} =	= 50 V, I _D = 0.47 A	0.50	-	-	S
Dynamic							
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,		140	-	pF
Output Capacitance	C _{oss}	$V_{DS} = 25 \text{ V},$		-	42	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.	.0 MHz, see fig. 5	-	9.6	-	1
Total Gate Charge	Qg		I _D = 2.7 A, V _{DS} = 200 V, see fig. 6 and 13 ^b	-	-	8.2	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	1.8	
Gate-Drain Charge	Q _{gd}	see lig. 6 and 13 5		-	-	4.5	
Turn-On Delay Time	t _{d(on)}			-	7.0	-	
Rise Time	t _r	$V_{DD} = 125 \text{ V}, \text{ I}_{D} = 2.7 \text{ A},$ $R_{g} = 24 \ \Omega, \text{ R}_{D} = 45 \ \Omega, \text{ see fig. } 10^{\text{ b}}$		-	7.6	-	ns
Turn-Off Delay Time	t _{d(off)}			=	16	-	
Fall Time	t _f			-	7.0	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.0	-	
Internal Source Inductance	L _S			-	6.0	-	nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S		MOSFET symbol			0.79	
Pulsed Diode Forward Current ^a	I _{SM}	showing the integral reverse p - n junction diode		-	-	6.3	А
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 0.79 A, V _{GS} = 0 V ^b		-	-	2.0	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 2.7 A, dI/dt = 100 A/μs ^b		=	190	390	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.64	1.3	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	ırn-on time is negligible (turn	-on is dor	ninated b	y L _S and	L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300~\mu s;$ duty cycle $\leq 2~\%.$



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

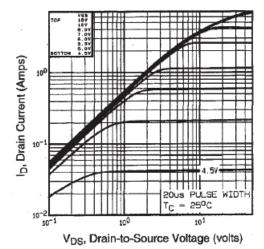


Fig. 1 - Typical Output Characteristics

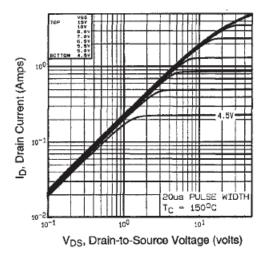


Fig. 2 - Typical Output Characteristics

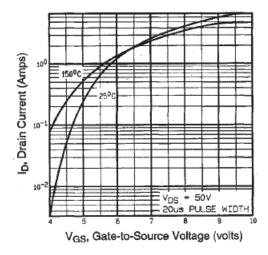


Fig. 3 - Typical Transfer Characteristics

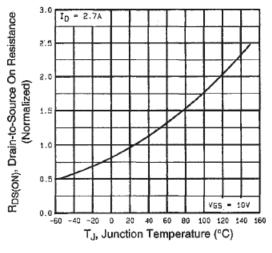


Fig. 4 - Normalized On-Resistance vs. Temperature

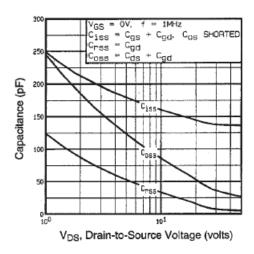


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

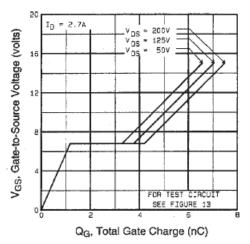


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



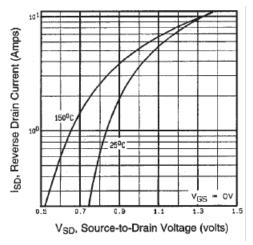


Fig. 7 - Typical Source-Drain Diode Forward Voltage

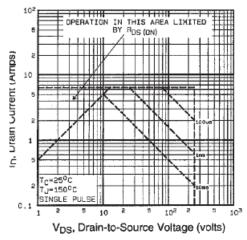


Fig. 8 - Maximum Safe Operating Area

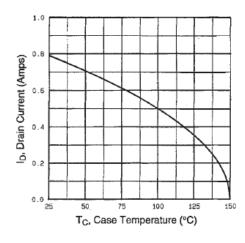


Fig. 9 - Maximum Drain Current vs. Case Temperature

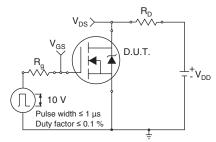


Fig. 10a - Switching Time Test Circuit

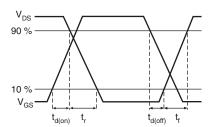


Fig. 10b - Switching Time Waveforms

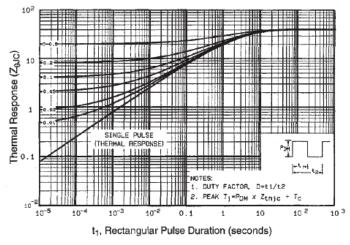


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



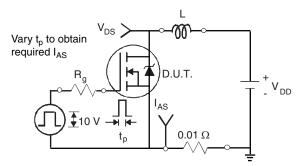


Fig. 12a - Unclamped Inductive Test Circuit

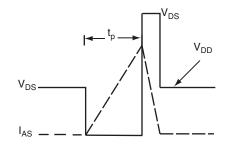


Fig. 12b - Unclamped Inductive Waveforms

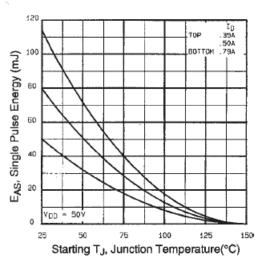


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

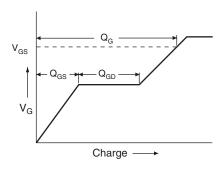


Fig. 13a - Basic Gate Charge Waveform

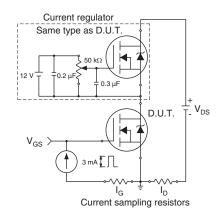
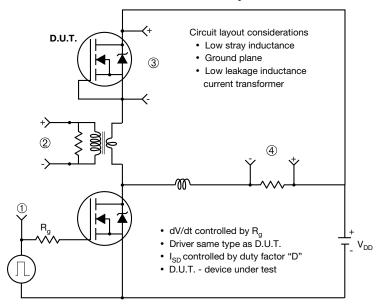


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



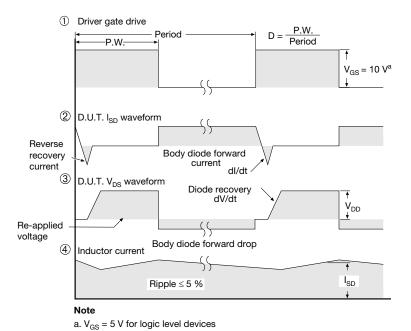
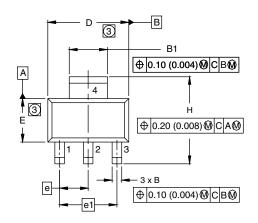


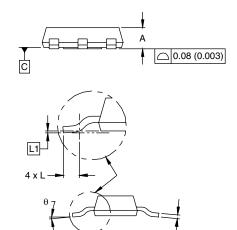
Fig.14 - For N-Channel



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SOT-223 (HIGH VOLTAGE)





DIM.	MILLI	METERS	INCHES		
	MIN.	MAX.	MIN.	MAX.	
Α	1.55	1.80	0.061	0.071	
В	0.65	0.85	0.026	0.033	
B1	2.95	3.15	0.116	0.124	
С	0.25	0.35	0.010	0.014	
D	6.30	6.70	0.248	0.264	
E	3.30	3.70	0.130	0.146	
е	2.30 BSC		0.0905 BSC		
e1	4.60 BSC		0.181	BSC	
Н	6.71	7.29	0.264	0.287	
L	0.91	-	0.036	=	
L1	0.061 BSC		0.0024	4 BSC	
θ	-	10'	-	10'	

ECN: S-82109-Rev. A, 15-Sep-08

DWG: 5969

Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension do not include mold flash.
- 4. Outline conforms to JEDEC outline TO-261AA.



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